EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	20	high near3 resolution with two adj4 (phase) near5 two	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 08:36
L2	216	high near3 resolution with two adj4 (phase)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 08:48
L3	27	high near3 resolution with two adj4 (phase) and (ccd or cmos)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 08:56
L4	71	high near3 resolution with two adj4 (phase) and (ccd or cmos or sensor)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 09:06
L5	464	257/246-248.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 09:06
L6	0	257/246-248.ccls. and highn near4 resolution	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 09:07
L7	31	257/246-248.ccls. and high near4 resolution	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 09:07

L10	46	(chang$4 or select$4) with mode with high with low with resolution and shift adj register	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 11:43
L11	37	(chang$4 or select$4) with mode with high with low with resolution and shift adj register and (clock or phase)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 11:44
L12	28	(chang$4 or select$4) with mode with high with low with resolution and shift adj register and (clock or phase)and gate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 11:50
L13	53	high with low with resolution with phase and shift adj register	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/17 11:51

IEEE *Xplore®*
RELEASE 2.3

Welcome United States Patent and Trademark Office

□ **Search Results**

BROWSE   SEARCH   IEEE XPLORE GUIDE

Results for "((((((phase)<in>metadata))<and>(high <near> resolution<in>metadata)))<and..."   ☑ e-mail
Your search matched **3** of **2178** documents.
A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

» **Search Options**

View Session History

New Search

Modify Search

((((((phase)<in>metadata))<and>(high <near> resolution<in>metadata)))<and>(shift [**Search**]

☐ Check to search only within this results set

Display Format: ◉ Citation   ○ Citation & Abstract

» **Key**

IEEE JNL	IEEE Journal or Magazine
IET JNL	IET Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IET CNF	IET Conference Proceeding
IEEE STD	IEEE Standard

[**view selected items**]   Select All   Deselect All

☐ **1. A 1/3-in 510(H)×492(V) CCD image sensor with mirror image function**
Hojo, J.; Naito, Y.; Mori, H.; Foujikawa, K.; Kato, N.; Wakayama, T.; Komatsu,
Electron Devices, IEEE Transactions on
Volume 38, Issue 5, May 1991 Page(s):954 - 959
Digital Object Identifier 10.1109/16.78364

AbstractPlus | Full Text: PDF(444 KB)   IEEE JNL
Rights and Permissions

☐ **2. A distributed BIST technique for diagnosis of MCM interconnections**
Pendurkar, R.; Chatterjee, A.; Zorian, Y.;
Test Conference, 1998. Proceedings. International
18-23 Oct. 1998 Page(s):214 - 221
Digital Object Identifier 10.1109/TEST.1998.743154

AbstractPlus | Full Text: PDF(540 KB)   IEEE CNF
Rights and Permissions

☐ **3. Dynamic focussing and ultrasonic imaging**
Martin, M.; Piquard, J.;
Acoustics, Speech, and Signal Processing, IEEE International Conference on I
Volume 7, May 1982 Page(s):1513 - 1515

AbstractPlus | Full Text: PDF(44 KB)   IEEE CNF
Rights and Permissions

Help   Contact Us   Privacy &

Indexed by
Inspec°

© Copyright 2006 IEEE –